

March 2006

# FDD8782/FDU8782 N-Channel PowerTrench® MOSFET

**25V, 35A, 11m**Ω

#### **General Description**

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low ros(on) and fast switching speed.

#### **Application**

- Vcore DC-DC for Desktop Computers and Servers
- VRM for Intermediate Bus Architecture

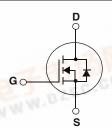
#### **Features**

- Max  $r_{DS(on)} = 11.0 \text{m}\Omega$  at  $V_{GS} = 10 \text{V}$ ,  $I_D = 35 \text{A}$
- Max  $r_{DS(on)} = 14.0 \text{m}\Omega$  at  $V_{GS} = 4.5 \text{V}$ ,  $I_D = 35 \text{A}$
- Low gate charge:  $Q_{g(10)} = 18nC(Typ)$ ,  $V_{GS} = 10V$
- Low gate resistance
- Avalanche rated and 100% tested
- RoHS Compliant









#### MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Symbol Parameter		Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage		25	V
$V_{GS}$	Gate to Source Voltage		±20	V
	Drain Current -Continuous (Package Limited)		35	
ID	-Continuous (Die Limited)		54	Α
	-Pulsed	(Note 1)	321	F (0)
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 2)		70	mJ
$P_{D}$	Power Dissipation		50	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature		-55 to 175	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case TO-252,TO-251	3.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient TO-252,TO-251	100	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient TO-252,1in <sup>2</sup> copper pad area	52	°C/W

### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD8782	FDD8782	TO-252AA	13"	12mm	2500 units
FDU8782	FDU8782	TO-251AA	N/A(Tube)	N/A	75 units
FDU8782	FDU8782_F071	TO-251AA	N/A(Tube)	N/A	75 units

Electrical Characteristics	$T_J$ = 25°C unless otherwise noted
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**Parameter** 

Off Characteristics						
B <sub>VDSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	25			V
$\frac{\Delta B_{VDSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25°C		14.3		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 20V, V <sub>GS</sub> = 0V			1 250	μА
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±20V			±100	nA

**Test Conditions** 

Min

Тур

Max

Units

#### **On Characteristics**

Symbol

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.2	1.7	2.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, referenced to 25°C		-6.5		mV/°C
		V <sub>GS</sub> = 10V, I <sub>D</sub> = 35A		8.5	11.0	
r <sub>DS(on)</sub> Drain to S	Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 35A$		11.0	14.0	m()
		$V_{GS} = 10V, I_D = 35A$ $T_J = 175^{\circ}C$		12.1	18.0	- mΩ

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	\\ - 12\\ \\ - 0\\	920	1220	pF
Coss	Output Capacitance	$V_{DS} = 13V, V_{GS} = 0V,$ = 1MHz	230	310	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 111112	160	240	pF
$R_g$	Gate Resistance	f = 1MHz	1.4		Ω

#### **Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time		7	14	ns
t <sub>r</sub>	Rise Time	$V_{DD} = 13V, I_{D} = 35A$ $V_{GS} = 10V, R_{GS} = 9\Omega$	9	18	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = 10V, N <sub>GS</sub> = 952	22	36	ns
t <sub>f</sub>	Fall Time		14	25	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> = 0V to 10V	18	25	nC
$Q_g$	Total Gate Charge	$V_{GS} = 0V \text{ to } 5V$ $V_{DD} = 13V$ $I_{D} = 35A$	9.4	13	nC
$Q_{gs}$	Gate to Source Gate Charge	$I_0 = 33A$ $I_0 = 1.0 \text{mA}$	3.1		nC
$Q_{gd}$	Gate to Drain "Miller" Charge	.g	4.0		nC

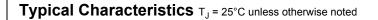
#### **Drain-Source Diode Characteristics**

V		V <sub>GS</sub> = 0V, I <sub>S</sub> = 35A	0.96	1.25	V	
V SD		V <sub>GS</sub> = 0V, I <sub>S</sub> = 15A	0.86	1.2		
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 35A$ , di/dt = $100A/\mu s$	25	38	ns	
Q <sub>rr</sub>	Reverse Recovery Charge	$I_F = 35A$ , di/dt = $100A/\mu s$	17	26	nC	

Notes:

1: Pulse time < 300us, Duty cycle = 2%.

2: Starting  $T_J = 25$ °C, L = 0.3mH,  $I_{AS} = 21.7$ A ,  $V_{DD} = 23$ V,  $V_{GS} = 10$ V.



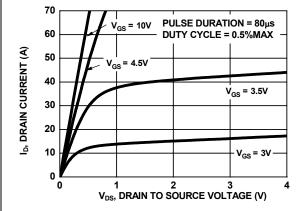


Figure 1. On Region Characteristics

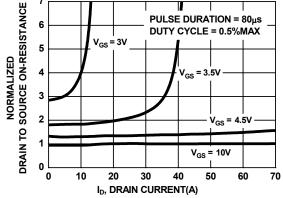


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

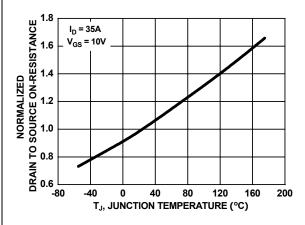


Figure 3. Normalized On Resistance vs Junction Temperature

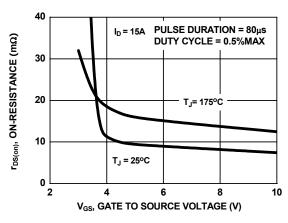


Figure 4. On-Resistance vs Gate to Source Voltage

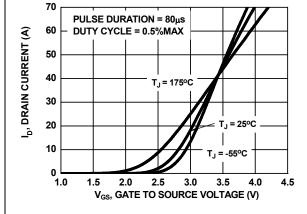


Figure 5. Transfer Characteristics

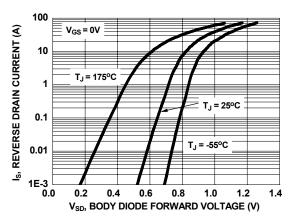
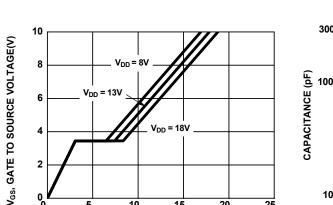


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

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**Typical Characteristics** T<sub>J</sub> = 25°C unless otherwise noted



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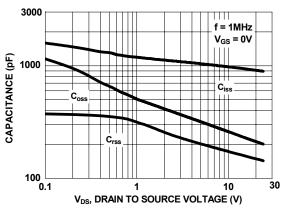


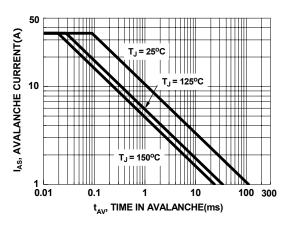
Figure 7. Gate Charge Characteristics

Qg, GATE CHARGE(nC)

4

0

Figure 8. Capacitance vs Drain to Source Voltage



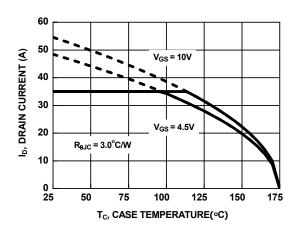
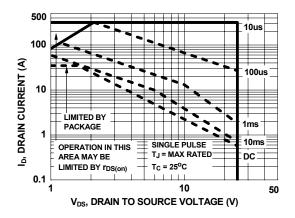


Figure 9. Unclamped Inductive Switching Capability

Figure 10. Maximum Continuous Drain Current vs **Case Temperature** 



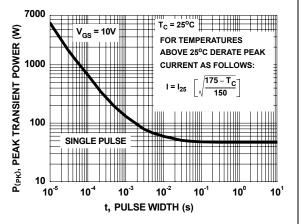


Figure 11. Forward Bias Safe Operating Area

Figure 12. Single Pulse Maximum Power Dissipation



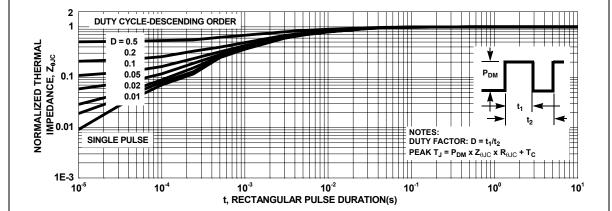


Figure 13. Transient Thermal Response Curve

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